

**Notice of References Cited**Application/Control No.  
**09/763,092**Applicant(s)/Patent Under Reexam  
**Miyajima**Examiner  
**Daniel G. DePumpo**Art Unit  
**3611**

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**U.S. PATENT DOCUMENTS**

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification</b> <sup>2</sup>	
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N						
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages					
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